

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 1.5 KV (not Include).

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product is compliant with the RoHS & HF.)

2. Parts Number Code

С	1206	N	473	J	101	Т
(1)	(2)	(3)	(4)	(5)	(6)	(7)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
J	± 5.00 %	More Than 10 pF

HVC-021-2005

(2)Chip Size

Code	Length×Width	unit : mm(inch)
1206	3.20× 1.60	(.126× .063)

(6)Rated Voltage

Code	Rated Voltage (Vdc)
101	100

(3) Temperature Characteristics

N	NPO	-55°C~±125°C	30 ppm/℃	
	Characteristic	Range	Coefficient	
Code	Temperature	Temperature	Temperature	

(7)Tapping

Code	Туре
Т	Tape & Reel

(4)Capacitance

unit :pico farads(pF)

• • •	1	
Code	Nominal Capacitance (pF)	
473	47,000.0	

^{*} If there is a decimal point, it shall be expressed by an English capital letter R

3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ınce	Nominal Capacitance
I	NPO	More Than 10 pF	J (± 5.00 %)	E-12, E-24 series

3.2 E series(standard Number)

Standard No.	Application Capacitance											
E- 3	1.0			2.2			4.7					
E- 6	1.	.0	1	.5	2	.2	3	.3	4.	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
I	NPO	-55℃ ~ +125℃	25℃

5. Storage Condition

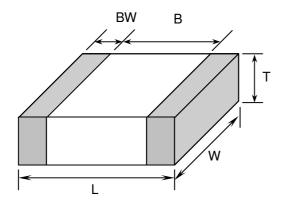
Storage Temperature : 5 to 40 °C Relative Humidity: 20 to 70 % Storage Time: 12 months max.





6. Dimensions

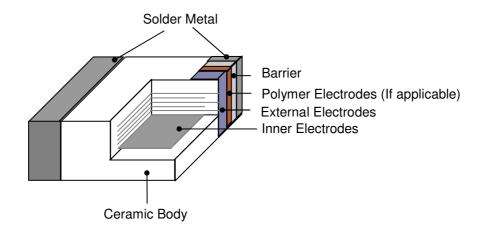
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	Т	B (min)	BW (min)
1206	3.20+ 0.40 /- 0.30	1.60+ 0.30 /- 0.20	1.60± 0.20	1.50	0.30

6.2 Termination Type:





MULTILAYER CERAMIC CHIP CAPACITORS

7. Performance

No.	Item		Specification	Test Condition		
1	Visua	I	No abnormal exterior appearance	Visual inspection		
2	Dimens	ion	See Page 2	Visual inspection		
3	Insulation $10,000 \mathrm{M}\Omega\mathrm{min}.$ Resistance		10,000M Ω min.	V≦500V, Rated Voltage Charge Time: 60sec. Is applied less than 50mA current.		
4	Capacitance	Class I NPO	Within The Specified Tolerance	Class I : Capacitance Frequency Voltage NPO 1KHz±10% 1.0±0.2Vrms Perform a heat temperature at 150±5°C for 30min. then place room temp. for 24±2hr.		
5	Q	Class I NPO	More Than 30pF : Q ≥ 1000			
6	Withstan Voltag	-	No dielectric breakdown or mechanical breakdown	V<500V : 200% Rated Voltage Voltage ramp up rate ≤ 500v/sec for 1~5 sec. charge/discharge Current is less than 50mA. ※ Withstanding voltage testing requires immersion of the element in a isolation fluid prevent arcing on the chip surface, at voltage over 1000Vdc.		
7	Temperature Capacitance Coefficient	Class I	Char. Temp. Range Cap. Change(%) NPO -55°C ~+125°C ± 30 ppm/°C	Class I: [C2-C1/C1(T2-T1)] × 100% T1: Standard temperature (25°C) T2: Test temperature C1:Capacitance at standard temperature(25°C) C2: Capacitance at test temperature (T2)		
8	Adhesive S of Termin		No indication of peeling shall occur on the terminal electrode.	Pull force shall be applied for 10 ± 1 second. $\leq 06035N (= 0.5 \text{ Kg} \cdot \text{f})$ > $060310N (= 1.0 \text{ Kg} \cdot \text{f})$		
9		Appear- ance C-Meter	No mechanical damage shall be occur. Capacitance Change Char. Cap. Change NPO ≤ ± 5.0%	Bending shall be applied to the 1.0 mm with 1.0 mm/sec. The duration of the applied forces shall be 5 ± 1sec R230 Bending Bending Limit C Meter 45±1mm Bending		



MULTILAYER CERAMIC CHIP CAPACITORS

No.	Ite	em	Speci	fication	Test Condition		
10	Solderability		More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve .		Solder Temperature: 245± 5°C Dip Time: 5 ± 0.5 sec. Immersing Speed: 25±10% mm/s Solder: Lead Free Solder Flux: Rosin Preheat: At 80~120 °C for 10~30sec.		
11	То	Soldering Heat Capacit- ance Class I Within ± 2.5% (NPO) ±0.25pFwhich is larger of in		Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value	Class Π capacitor shall be set for 48±4 hours room temperature after one hour heat treatment at 150 +0/-10 $^{\circ}$ C before initial measure. Preheat: At 150±10 $^{\circ}$ C For 60 $^{\circ}$ 120sec. Dip: Solder Temperature of 260±5 $^{\circ}$ C Dip Time: 10±1sec.		
		Q Class I Insulation Resistance Withstand Voltage	To satisfy the speci To satisfy the speci To satisfy the speci	fied initial value	Immersing Speed: 25±10% mm/s Flux:Rosin Measure at room temperature after cooling for Class I: 24 ± 2 Hours		
12	Tempera ture Cycle	Appear- ance Capacit- ance Q Class I Insulation Resistance	No mechanical dan Characteristic Class I (NPO) To satisfy the speci	Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value fied initial value	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30 2 25 3 3 Max Rated Temp. +3/-0 30 4 25 3 Measure at room temperature after cooling for Class I :24 ± 2 Hrs Solder the capacitor on P.C. board shown in		
13	·	Appear- ance Capacit- ance Q Class I Insulation Resistance	(NPO)	Cap. Change Within ± 5.0% or ±0.5pF whichever is larger of initial value	Fig 2. before testing. Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150+0/-10 ℃ before initial measure. Temperature: 40± 2℃ Relative Humidity: 90 ~ 95%RH Test Time: 500 +12/-0Hr Measure at room temperature after cooling for Class I: 24 ± 2Hrs Solder the capacitor on P.C. board shown in Fig 2. before testing.		

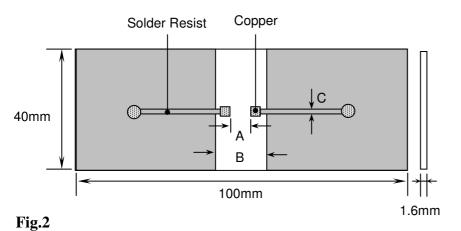


MULTILAYER CERAMIC CHIP CAPACITORS

No.	Ite	m	Specifi	cation	Test Condition
14	High Temperature Load (Life Test)	Appearance Capacitance Q Class I Insulation Resistance	No mechanical dar Characteristic Class I (NPO) More Than 30pF : 1,000MΩmin.	Cap. Change Within ±3.0% or ± 0.3pFwhichever is larger	Class II capacitors applied DC voltage (following table) is applied for one hour at maximum operation temperature ±3°C then shall be set for 48±4 hours at room temperature and the initial measurement shall be conducted. Applied Voltage : 100%Rated Voltage Test Time : 1000 +12/-0Hr Current Applied : 50 mA Max. Measure at room temperature after cooling for Class I : 24 ± 2 Hours
15	Vibration	Appear- ance Capacit- ance Q Class I Insulation Resistance	Characteristic Class I (NPO) To satisfy the spec	Cap. Change Within ± 2.5% or ± 0.25pFwhichever is larger	P-P changing the frequencies from 10Hz to



Fig.1
P.C. Board for Bending Strength Test

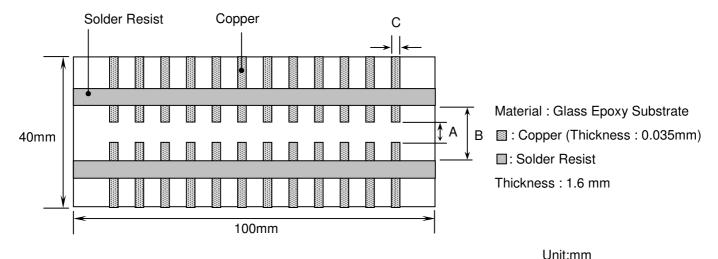


Material : Glass Epoxy Substrate

■: Copper (Thickness: 0.035mm)

☐: Solder Resist

Test Substrate



			O'IIIC.ITIITI
Туре	A	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
1825	3.5	7.0	6.9
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6
2225	4.5	8.0	7.0

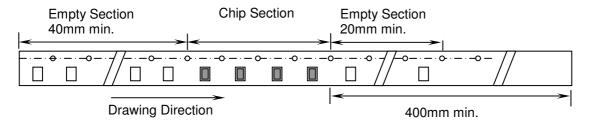


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/0805		
Material T≤0.39mm		T≦0.70mm	T≦1.00mm	T>1.00mm	
Paper 15,000 pcs/R		10,000 pcs/Reel	4,000 pcs/Reel	NA	
Plastic	NA	NA	NA	3,000 pcs/Reel	

Tape	1206					
Material	T≦1.00mm	1.00mm < T ≦ 1.25mm	T>1.25mm			
Paper	4,000 pcs/Reel	NA	NA			
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel			

Tape		1808/1210	
Material	T \leq 1.25mm 1.25mm $<$ T \leq 2.40r		T>2.40mm
Paper	NA	NA	NA
Plastic	3,000 pcs/Reel	1,000/2,000 pcs/Reel	500/1,000 pcs/Reel

Tape	1812/221	1/2220	1825/2	2208	
Material	T≦2.20mm T>2.20mm		T≦2.20mm T>2.20mm		T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1,000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1,000 pcs/Reel

NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

 $5 g \cdot f \le Peel-Off Force \le 70 g \cdot f$

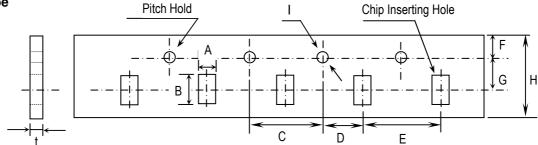
8.4.2 Measure Method







8.5 Paper Tape

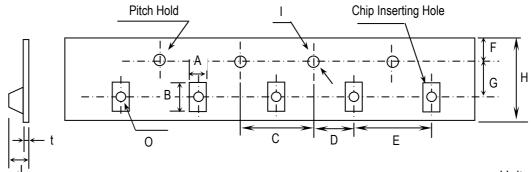


Unit:mm

TYPE	Α	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Туре	A	В	C	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				

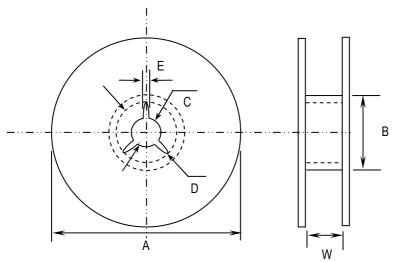




Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material : Polystyrene



Unit:mm

Туре	Α	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±2.0	φ 60±2.0				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						



Precautionary Notes:

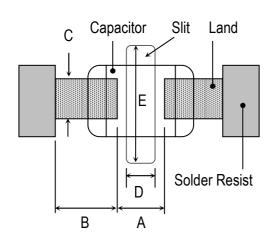
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

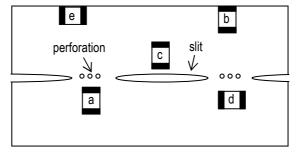
2.1 Size and recommend land dimensions for reflow soldering.



EIA Code	Chip	(mm)	Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		1
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		1
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

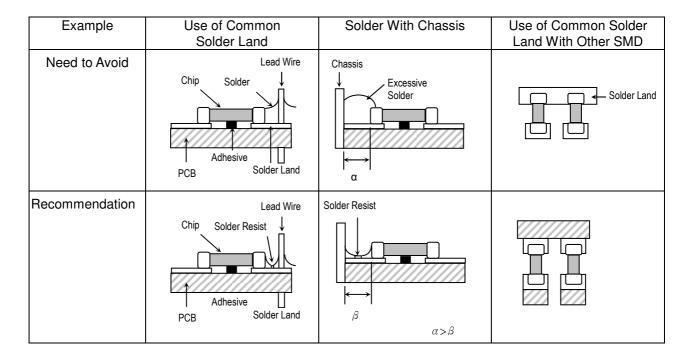
2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board. Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



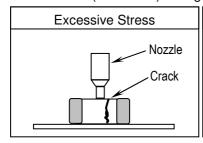


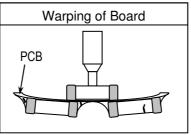
2.3 Layout Recommendation

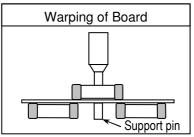


3. Mounting

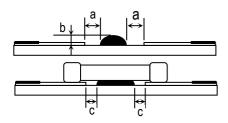
3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.







3.2 Amount of Adhesive



Example: 0805 & 1206

	a	0.2mm min.
l	0	70 ~ 100 μm
(C	Do not touch the solder land



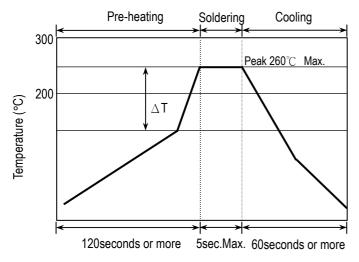


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at Peak Temperature.. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Peak Temp.($^{\circ}$ C) / Duration (sec)
1206/0805/0603	Δ T ≤ 100~150°C max.
Pb-Sn Solder	250°C (max.) / 3sec(max.)
Lead Free Solder	260°C (max.) / 5sec(max.)

Recommended solder compositions

Sn-37Pb (Pb - Sn Solder)

Sn-3.0Ag-0.5Cu (Lead Free Solder)

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

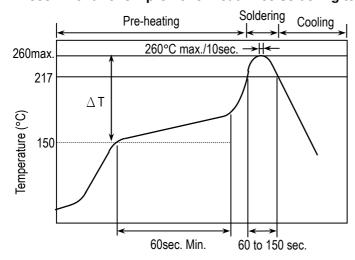
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3 °C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (J-STD-020D)



The cycles of soldering : Twice (max.)

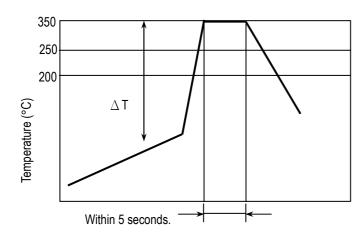
Soldering Method	Change in Temp.(°C)
1206 and Under	∆ T ≦ 190 °C
1210 and Over	∆ T ≦ 130 °C





4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	∆ T ≦ 130 °C

How to Solder Repair by Solder Iron

1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

- 2) recommended solder iron condition
 - a.) Preheating Condition: Board and components should be preheated sufficiently at 150 ℃ or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.

Higher potential of crack

- c.) Soldering iron tip diameter shall not exceed 3mm.
- d.) Temperature of iron tip shall not exceed 350 °C., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
- f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.

Lower potential of crack

g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Bending **Twist**

5.2 There is a potential of crack if board is warped due to excessive load by check pin





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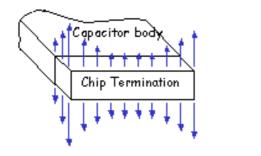


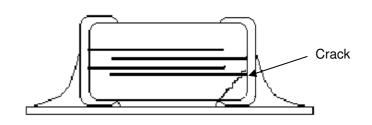


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



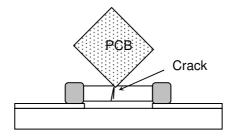


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.